

Improvements of the Measurement System of the Soft X-ray XAFS Beamline

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Abstract

This paper describes recent improvements of the measurement system of the soft-X-ray XAFS beamline at BL-10 at SR Center. They include installation of the windowless-type solid-state-detector for measurements in the fluorescent radiation mode and of the sample cooling device. Furthermore, a system has been constructed by which simultaneous recording of XAFS spectra in different modes, for example the total electron yield mode and the fluorescent radiation mode, can be made. It enables us to obtain structural information of different kinds from the same irradiated area of the sample and allow to make direct comparison of spectra. An ion-beam gun has also been installed in the sample chamber to remove surface contamination prior to measurements. Some examples of new XAFS spectra are shown.

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